

L19	23389	I16 and I17	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:20
L20	78	I18 and I19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:21
L21	230	waveform digitizer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:22
L22	1	I20 and I21	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:21
L23	16194	digitizer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:22
L24	11	I23 and I20	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:33
L25	8922	714/724 or 714/738 or 714/699 or 714/733 or 714/734 or 702/108 or 702/112 or 702/124 or 702/57 or 702/70	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:36
L26	1	I24 and I25	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:32

L27	3	I25 and I20	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:40
L28	76	I25 and I19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:41
L29	147812	signal generator or waveform generator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:41
L31	14	I28 and I29	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:42

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	MIMO chip	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:10
L2	284575	mixed-signal system-on-chip or SOC\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:11
L3	222	mixed signal IC\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:11
L4	1	testing and (next-generation SOC\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:12
L5	15550	single integrated circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:13
L6	284750	I2 or I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:14
L7	299863	I5 or I6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:14
L8	1	next-generation SOC\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:14

L9	21	on-chip integrated system	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:15
L10	2	on-chip integrated excitation/extraction system	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:15
L13	47	I2 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:16
L14	1	I13 and I5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:16
L15	871884	test\$3 and measur\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:17
L16	82156	I15 and (I13 or I7 or I9 or 10)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:18
L17	2195380	(CUT or circuit under test or DUT or device under test or UUT or unit under test)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:19
L18	17152	waveform generator or reference voltage generator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/01/23 13:19